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Temperature-Stable Dielectric Ceramics based on Na_{0.5}Bi_{0.5}TiO₃

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Abstract

Multiple ion substitutions to Na_{0.5}Bi_{0.5}TiO₃ give rise to favourable dielectric properties over

the technologically important temperature range -55 °C to 300 °C. A relative permittivity, ε_r,

= 1300 ± 15 % was recorded, with low loss tangent, $\tan \delta \le 0.025$, for temperatures from

300°C to 0°C, increasing to 0.05 at -55 °C (1 kHz) in the targeted solid solution (1-

x)[0.85Na_{0.5}Bi_{0.5}TiO₃-0.15Ba_{0.8}Ca_{0.2}Ti_{1-y}Zr_yO₃]-xNaNbO₃: x = 0.3, y = 0.2. The ε_r -T plots for

NaNbO₃ contents x < 0.2 exhibited a frequency-dependent inflection below the temperature

of a broad dielectric peak. Higher levels of niobate substitution resulted in a single peak with

frequency dispersion, typical of a normal relaxor ferroelectric. Experimental trends in

properties suggest that the dielectric inflection is the true relaxor dielectric peak and appears as

an inflection due to overlap with an independent broad dielectric peak. Process-related cation

and oxygen vacancies and their possible contributions to dielectric properties are discussed.

Keywords: Dielectrics; sodium bismuth titanate; high-temperature

capacitor materials

1

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